

MDM1200F33-C3

3300V SiC Diode

FEATURES

- * Ultra low recovery loss with SiC-SBD.
- * Isolated heat sink (terminal to base).
- * RoHS

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item	Symbol	Unit	MDM1200F33-C3
Repetitive Peak Reverse Voltage	V _{RRM}	V	3,300
Forward Current	AC peak	A	1,200
	1ms		2,400
Operating Junction Temperature	T _{vi op}	°C	-40 ~ +150
Storage Temperature	T _{stg}	°C	-40 ~ +150 (1)
Isolation Test Voltage	Terminals-base	V _{ISO}	V _{RMS} 6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (2)
	Mounting (M6)	-	6 (3)

Notes: (1) Terminal temperature shall not exceed the specified temperature in any operation.
 (2) Recommended Value 1.8±0.2/15⁺⁰₋₃N·m (3) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Repetitive Reverse Current	I _{RRM}	mA	-	-	12	V _R =3,300V, T _{vi} =25°C
			-	25	65	V _R =3,300V, T _{vi} =150°C
Forward Voltage Drop	V _F	V	-	2.5	-	I _F =1,200A, T _{vi} =25°C
			-	4.97	6.0	I _F =1,200A, T _{vi} =150°C
Reverse Recovery Time	t _{rr}	μs	-	0.1	-	V _R =1,500V, I _F =1,200A, di/dt=-4500A/μs, L _S =100nH, T _{vi} =150°C, R _g =4.7Ω, C _{ge} =0.1μF (4)
Reverse Recovery Current	I _{rr}	A	-	200	-	
Reverse Recovery Charge	Q _{rr}	μC	-	25	-	
Reverse Recovery Loss	E _{rr}	J/P	-	0.01	0.12	
I ² t value	I ² t	kA ² s	13	-	-	T _{j start} =150°C, 10ms, V _R =0V, half-sinewave

PACKAGE CHARACTERISTICS

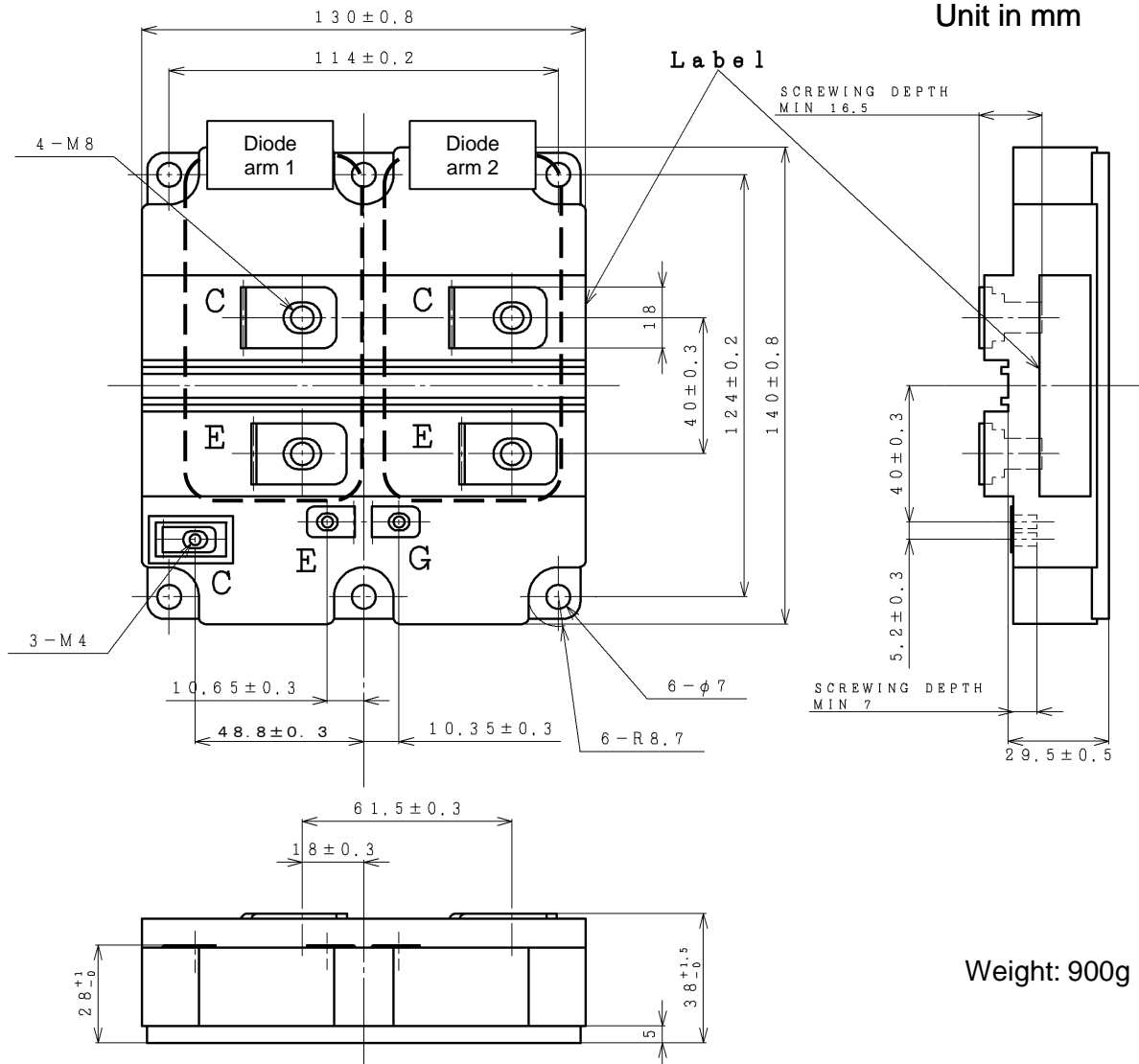
Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Terminal Resistance	R _{Ce}	mΩ	-	0.13	-	per arm, T _{vi} =25°C
Stray inductance module	L _{SCE}	nH	-	20	-	per arm
Thermal Impedance	R _{th(f-c)}	K/W	-	-	0.017	Junction to case (per arm)
Comparative tracking index	CTI	-	-	600	-	
Contact Thermal Impedance	R _{th(c-f)}	K/W	-	0.008	-	Case to fin (per module)

Notes: (4) Counter arm; MBN1200F33F-C3 VGE=+16V/-9V
 R_{Ce} value is the test condition's value for evaluation of the switching times, not recommended value.
 Please, determine the suitable R_{Ce} value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.
- * ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2.

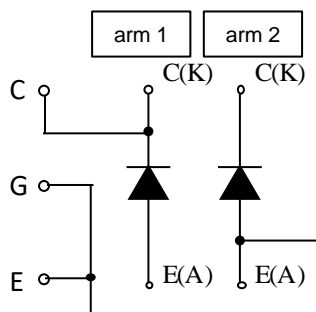
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OUTLINE DRAWING



Weight: 900g

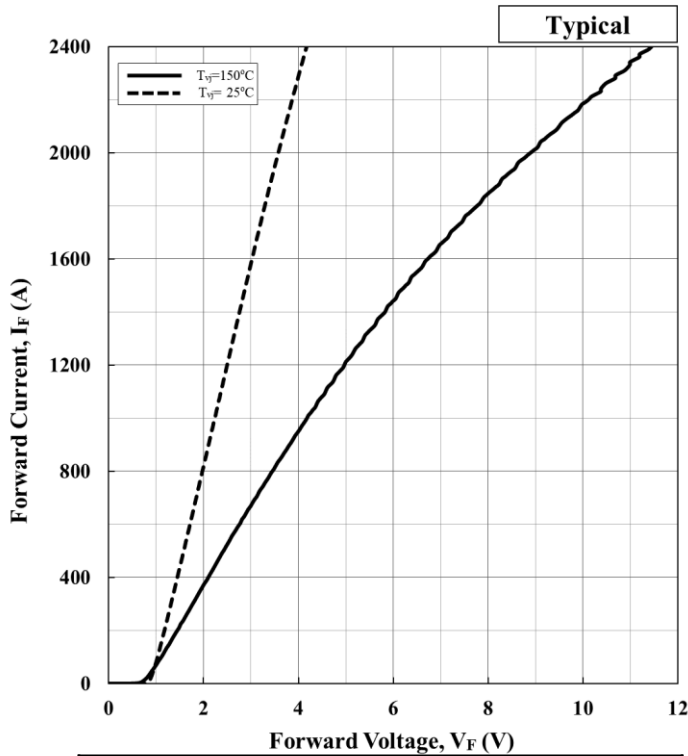
CIRCUIT DIAGRAM



Notice

- Arm1 and Arm2 are not able to use for series connection.
- Auxiliary terminal of Collector, Emitter and Gate are connected to main terminal at internally.

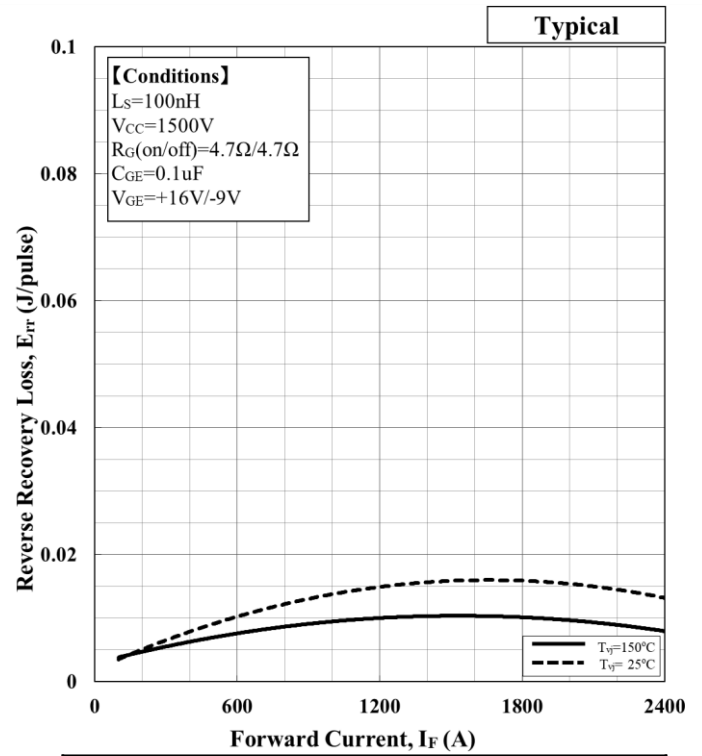
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$$V_F [V] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	a_3	a_2	a_1	a_0
25	5.28.E-11	-1.68.E-07	1.47.E-03	8.84.E-01
150	2.63.E-10	-1.43.E-07	3.28.E-03	7.86.E-01

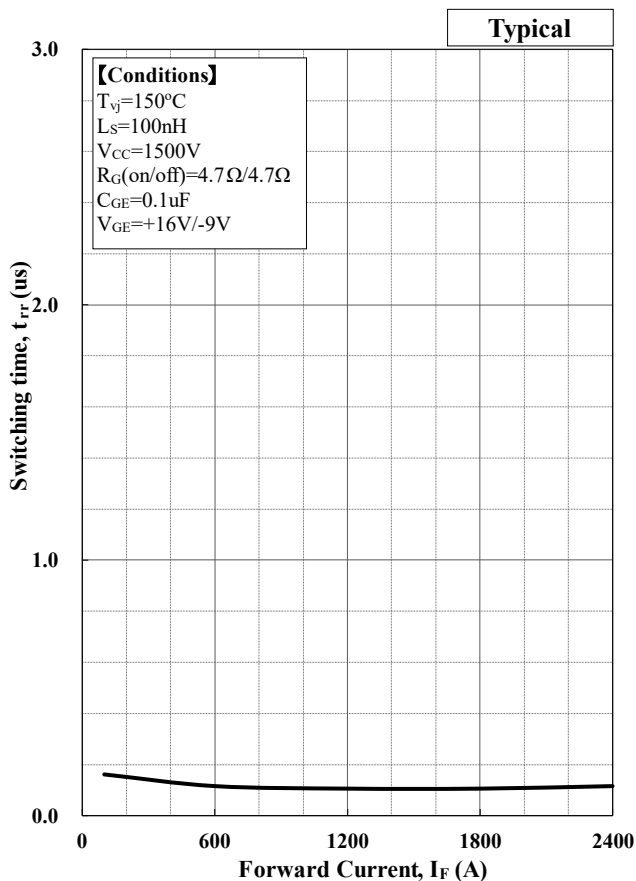
Forward Voltage of diode



$$E [J] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

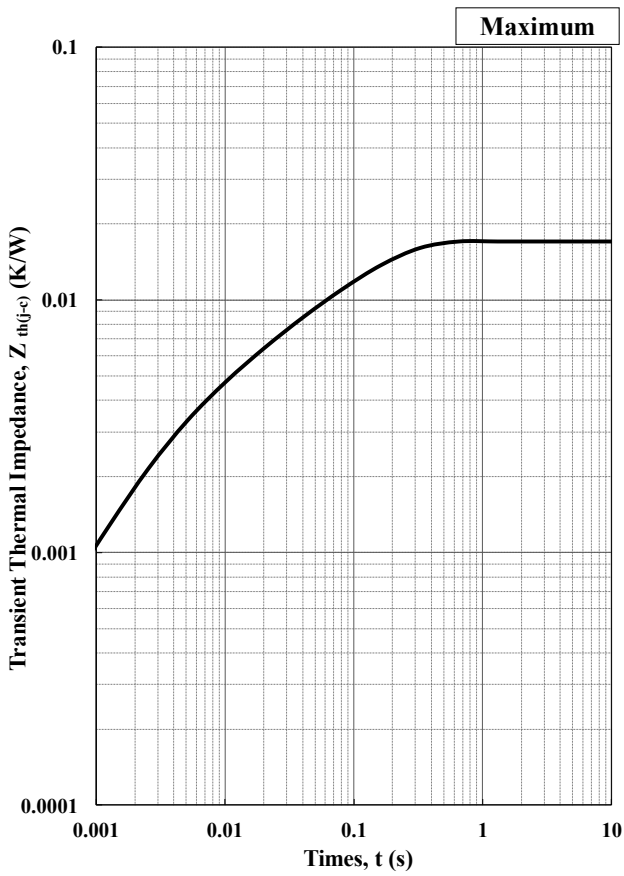
Temp.[°C]	a_3	a_2	a_1	a_0
25	0.00.E+00	-5.13.E-09	1.70.E-05	1.85.E-03
150	0.00.E+00	-3.20.E-09	9.80.E-06	2.85.E-03

Recovery loss vs. Forward current



Switching time vs. Forward Current

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Transient Thermal Impedance Curve

Foster model lumped circuit constant

n	1	2	3	4	Unit
R th, Diode [n]	3.20E-03	2.30E-03	9.51E-03	2.00E-03	[K/W]
C th, Diode [n]	9.37E-01	1.31E+01	1.05E+01	1.50E+02	[J/K]

Cauer model lumped circuit constant

n	1	2	3	4	Unit
R th, Diode [n]	4.32E-03	8.29E-03	3.72E-03	6.77E-04	[K/W]
C th, Diode [n]	8.03E-01	5.53E+00	1.65E+01	4.09E+02	[J/K]

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8. For handling other than described in this manual, follow the handling instructions (IGBT-HI-00002).

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- For inquiries relating to the products, please contact nearest representatives that is located "Inquiry" portion on the top page of a home page.
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